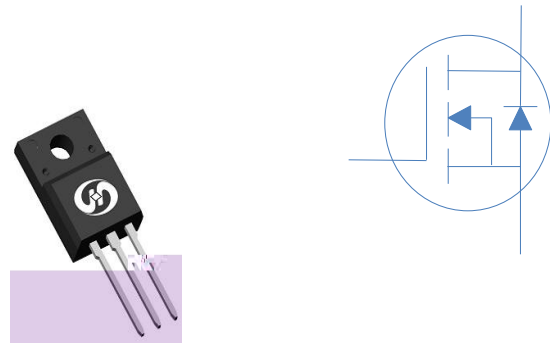


## 100V N-Ch Power MOSFET

$V_{DS}$		100	V
$R_{DS(on),typ}$	$V_{GS}=10V$	7.6	m
$I_D$ (Silicon Limited)		43.5	A

Part Number	Package	Marking
HGA080N10A	TO-220F	GA080N10A



### Absolute Maximum Ratings at $T_J=25^{\circ}C$ (unless otherwise specified)

Parameter	Symbol	Conditions	Value	Unit
Continuous Drain Current (Silicon Limited)	$I_D$	$T_C=25^{\circ}C$	44	A
		$T_C=100^{\circ}C$	31	
Drain to Source Voltage	$V_{DS}$	-	100	V
Gate to Source Voltage	$V_{GS}$	-	$\pm 20$	V
Pulsed Drain Current	$I_{DM}$	-	260	A
Avalanche Energy, Single Pulse	$E_{AS}$	$L=0.4mH, T_C=25^{\circ}C$	245	mJ
Power Dissipation	$P_D$	$T_C=25^{\circ}C$	33	W
Operating and Storage Temperature	$T_J, T_{stg}$	-	-55 to 175	$^{\circ}C$

### Absolute Maximum Ratings

Parameter	Symbol	Max	Unit
Thermal Resistance Junction-Ambient	$R_{JA}$	60	$^{\circ}C/W$
Thermal Resistance Junction-Case	$R_{JC}$	4.5	$^{\circ}C/W$

**Electrical Characteristics at  $T_J=25^{\circ}\text{C}$  (unless otherwise specified)**
**Static Characteristics**

Parameter	Symbol	Conditions	Value			Unit
			min	typ	max	
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=250\text{ A}$	100	-	-	V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}, I_D=250\text{ A}$	2.0	3.0	4.0	
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{GS}=0V, V_{DS}=100V, T_J=25^{\circ}\text{C}$	-	-	1	A
		$V_{GS}=0V, V_{DS}=100V, T_J=100^{\circ}\text{C}$	-	-	100	
Gate to Source Leakage Current	$I_{GSS}$	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	$\pm 100$	nA
Drain to Source on Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=20A$	-	7.6	8.8	m
Transconductance	$g_{fs}$	$V_{DS}=5V, I_D=10A$	-	38	-	S
Gate Resistance	$R_G$	$V_{GS}=0V, V_{DS}\text{ Open}, f=1\text{MHz}$	-	1.4	-	

**Dynamic Characteristics**

Input Capacitance	$C_{iss}$	$V_{GS}=0V, V_{DS}=50V, f=1\text{MHz}$	-	1576	-	pF
Output Capacitance	$C_{oss}$		-	350	-	
Reverse Transfer Capacitance	$C_{rss}$		-	7.0	-	
Total Gate Charge	$Q_g(10V)$	$V_{DD}=50V, I_D=20A, V_{GS}=10V$	-	25	-	nC
Gate to Source Charge	$Q_{gs}$		-	6	-	
Gate to Drain (Miller) Charge	$Q_{gd}$		-	8	-	
Turn on Delay Time	$t_{d(on)}$	$V_{DD}=50V, I_D=20A, V_{GS}=10V, R_G=10\text{ }\Omega$	-	7	-	ns
Rise time	$t_r$		-	4	-	
Turn off Delay Time	$t_{d(off)}$		-	19	-	
Fall Time	$t_f$		-	3	-	

**Reverse Diode Characteristics**

Diode Forward Voltage	$V_{SD}$	$V_{GS}=0V, I_F=20A$	-	0.9	1.2	V
Reverse Recovery Time	$t_{rr}$	$V_R=50V, I_F=20A, dI_F/dt=500A/\text{s}$	-	50	-	ns
Reverse Recovery Charge	$Q_{rr}$		-	212	-	nC

Fig 1. Typical Output Characteristics

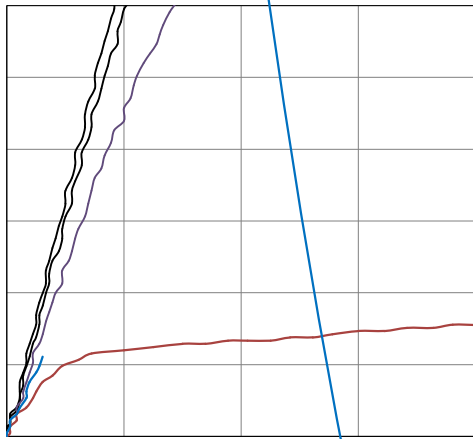


Figure 2. On-Resistance vs. Gate-Source Voltage

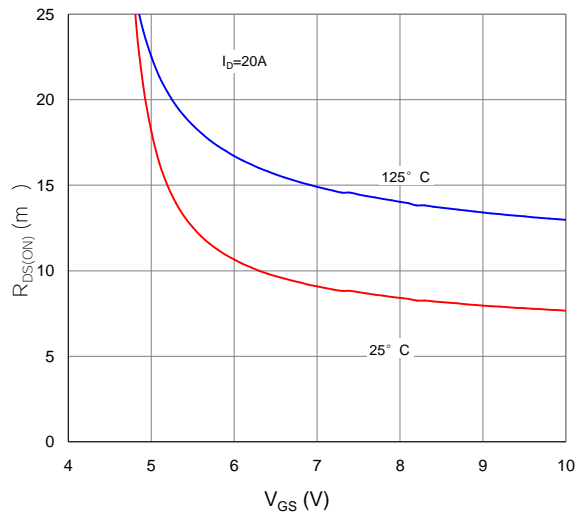


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

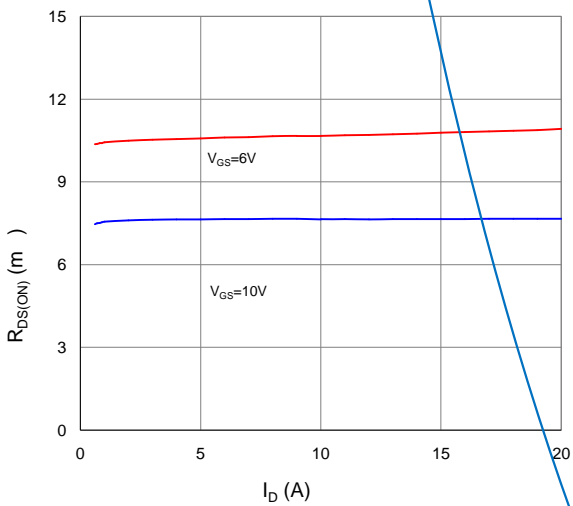


Figure 4. Normalized On-Resistance vs. Junction Temperature

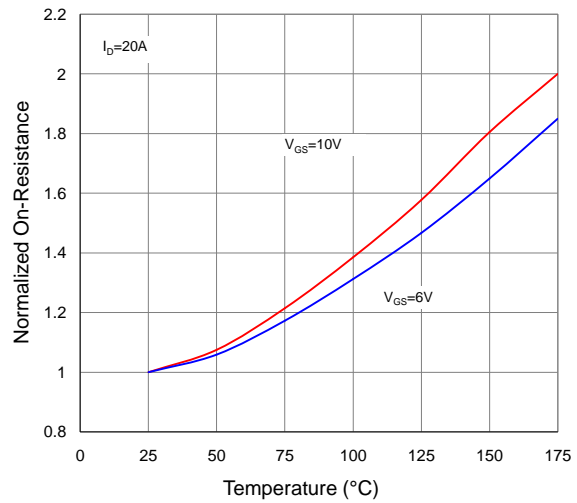


Figure 5. Typical Transfer Characteristics

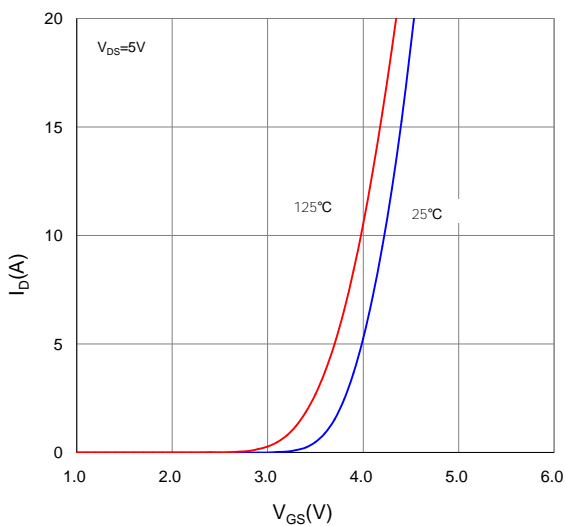


Figure 6. Typical Source-Drain Diode Forward Voltage

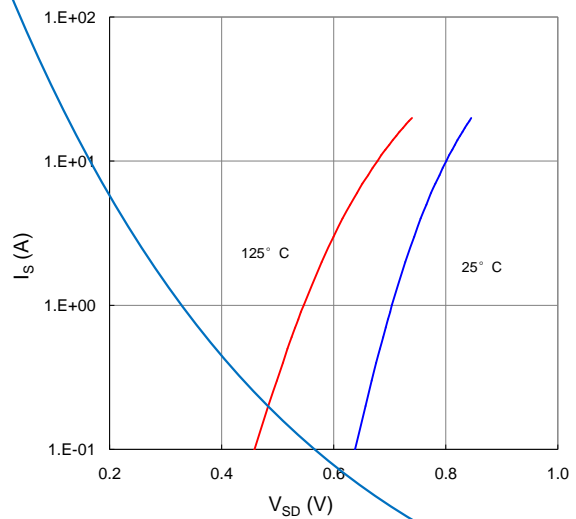


Figure 7. Typical Gate-Charge vs. Gate-to-Source Voltage

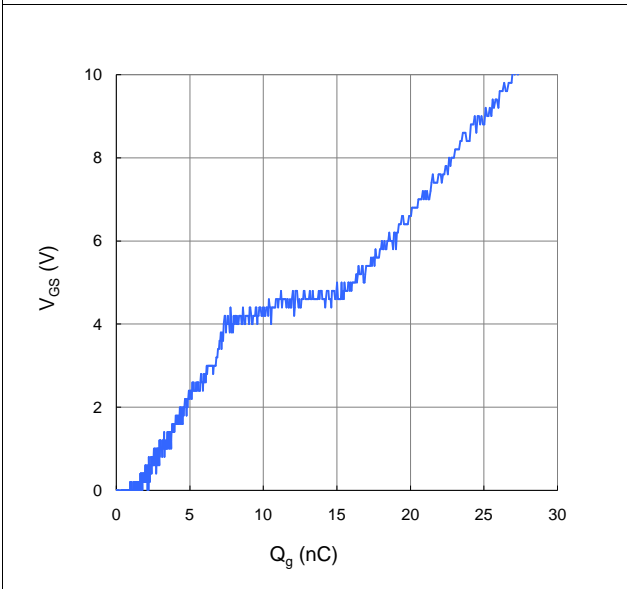


Figure 8. Typical Capacitance vs. Drain-to-Source Voltage

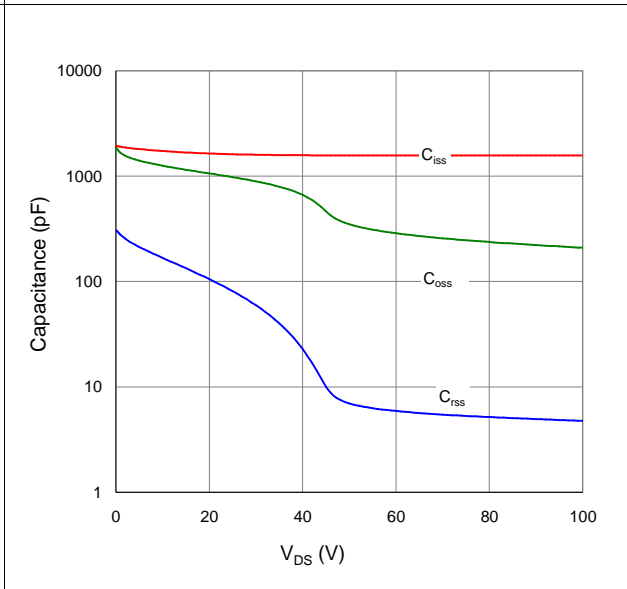


Figure 9. Maximum Safe Operating Area

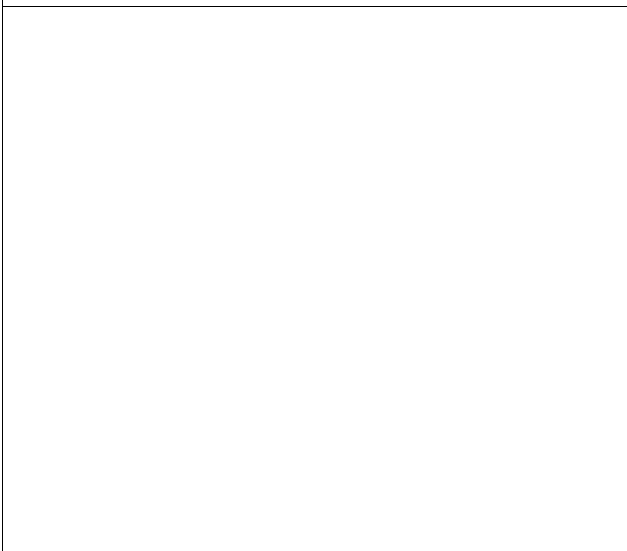


Figure 10. Maximum Drain Current vs. Case Temperature

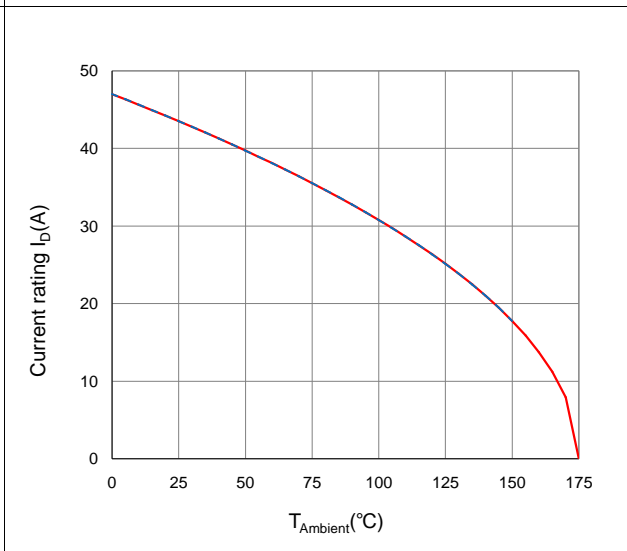
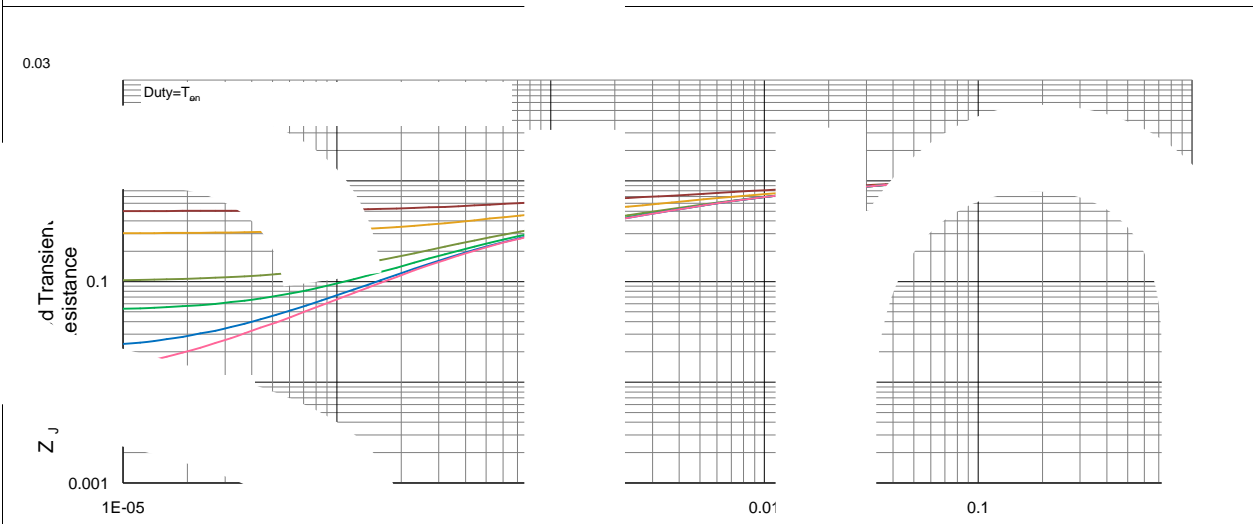
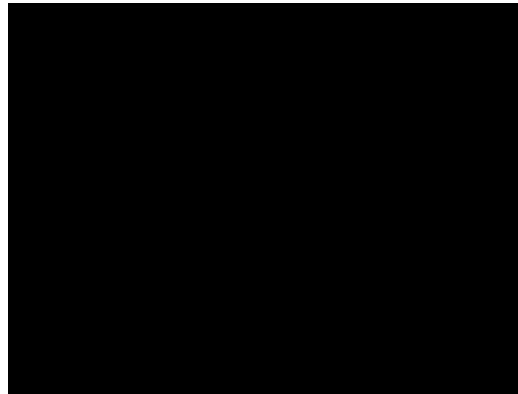


Figure 11. Normalized Maximum

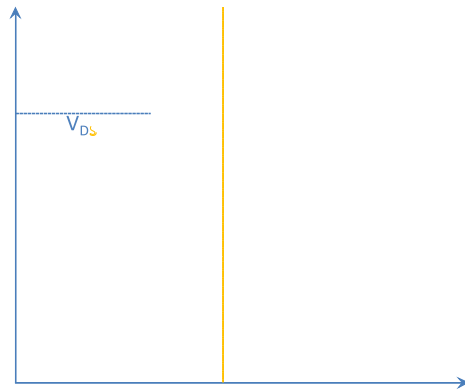
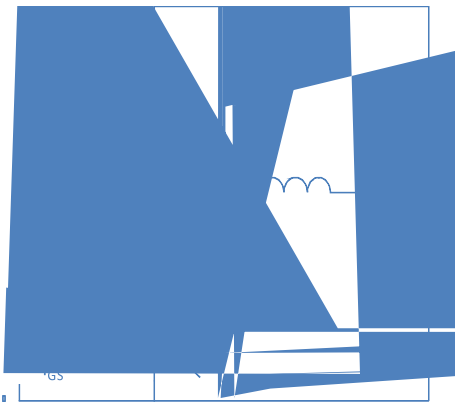
Thermal Impedance, Junction-to-Ambient



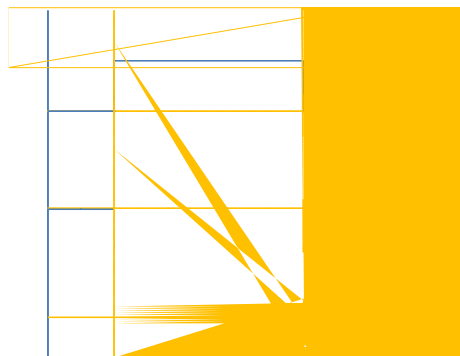
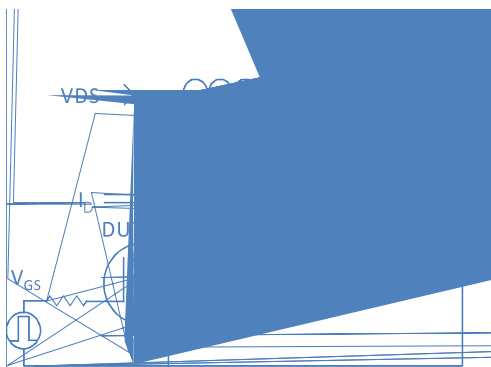
Inductive switching Test



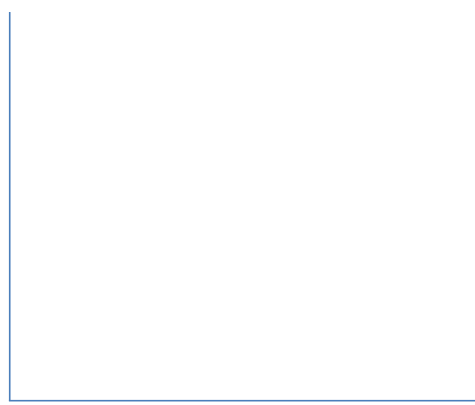
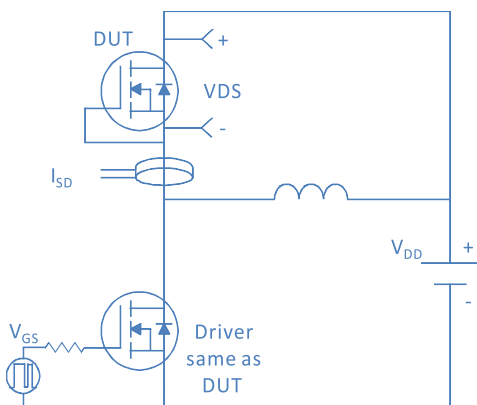
Gate Charge Test



Uclamped Inductive Switching (UIS) Test

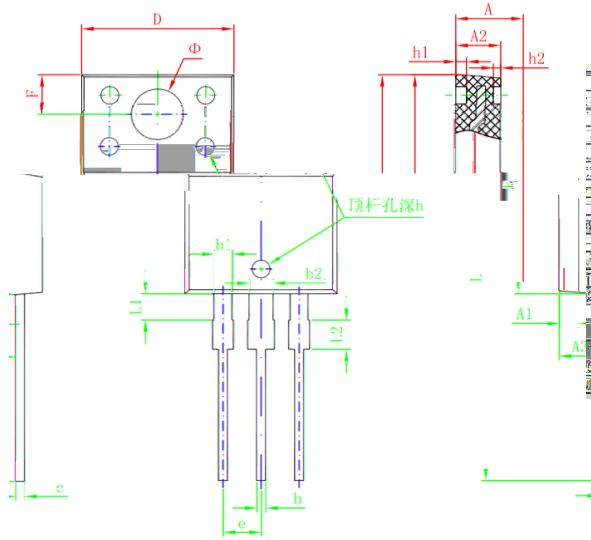


Diode Recovery Test



Package Outline

TO-220F, 3 Leads



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.800	3.200	0.110	0.126
A1	1.300 REF.		0.051 REF.	
A2	2.800		0.110	
b1	0.500	0.750	0.020	0.030
b2	1.100	1.350	0.043	0.053
c	1.500	1.750	0.059	0.069
e	0.500	0.750	0.020	0.030
h	0.900	1.200	0.035	0.047
h1	1.250	1.500	0.050	0.059
h2	2.540	2.700	0.100	0.106
L	2.700		0.106	
L1	0.812		0.032	0.032
L2	0.812		0.032	0.032
D	1.116		0.044	0.044